# FAIRCHILD

SEMICONDUCTOR®

December 2013

# FQU20N06L N-Channel QFET<sup>®</sup> MOSFET

60 V, 17.2 A, 42 mΩ

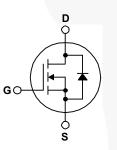
## Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

#### Features

- 17.2 A, 60 V,  $R_{DS(on)}$  = 42 m $\Omega$  (Max.) @ V<sub>GS</sub> = 10 V, I<sub>D</sub> = 8.6 A
- Low Gate Charge (Typ. 9.5 nC)
- Low Crss (Typ. 35 pF)
- 100% Avalanche Tested
- Low Level Gate Drive Requirements Allowing Direct
  Operation Form Logic Drivers





#### Absolute Maximum Ratings T<sub>c</sub> = 25°C unless otherwise noted.

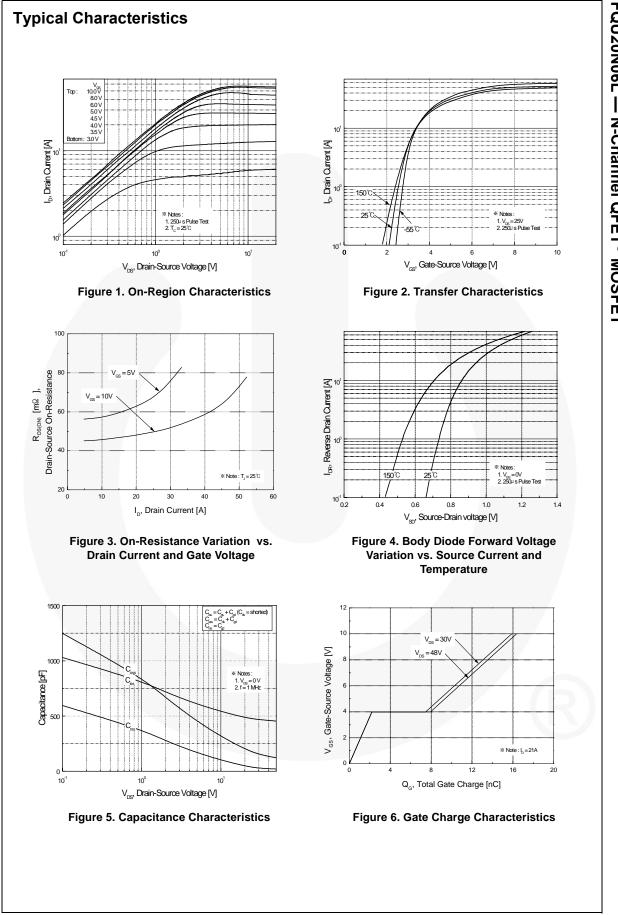
Symbol	Parameter	FQU20N06LTU	Unit
V <sub>DSS</sub>	Drain-Source Voltage	60	V
ID	Drain Current - Continuous ( $T_c = 25^{\circ}C$ )	17.2	A
	- Continuous (T <sub>C</sub> = 100°C)	10.9	A
I <sub>DM</sub>	Drain Current - Pulsed (Note 1)	68.8	A
V <sub>GSS</sub>	Gate-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)	170	mJ
I <sub>AR</sub>	Avalanche Current (Note 1)	17.2	A
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)	3.8	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	7.0	V/ns
P <sub>D</sub>	Power Dissipation ( $T_A = 25^{\circ}C$ ) *	2.5	W
	Power Dissipation ( $T_C = 25^{\circ}C$ )	38	W
	- Derate above 25°C	0.30	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to +150	°C
TL	Maximum lead temperature for soldering,      1/8" from case for 5 seconds.	300	°C

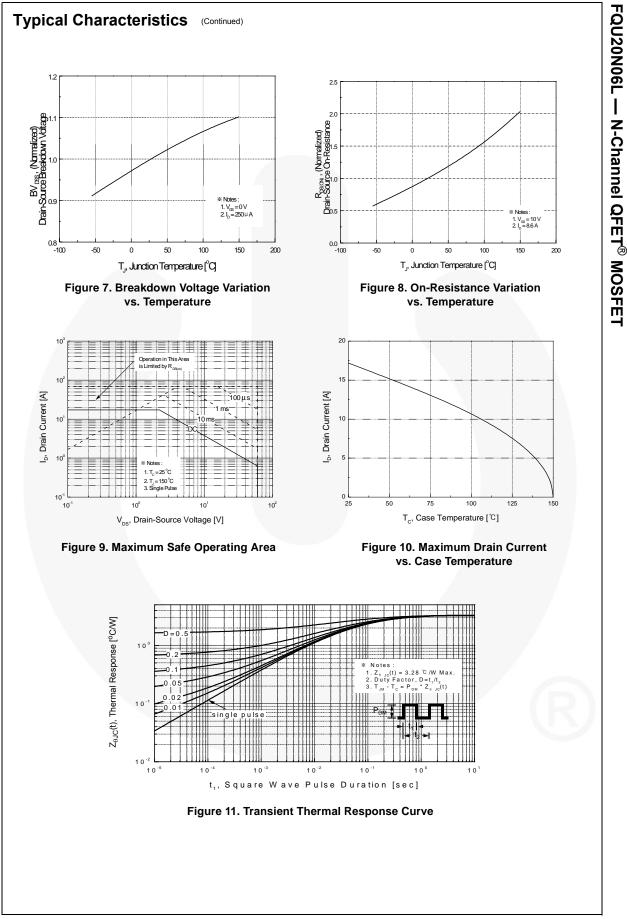
### Thermal Characteristics

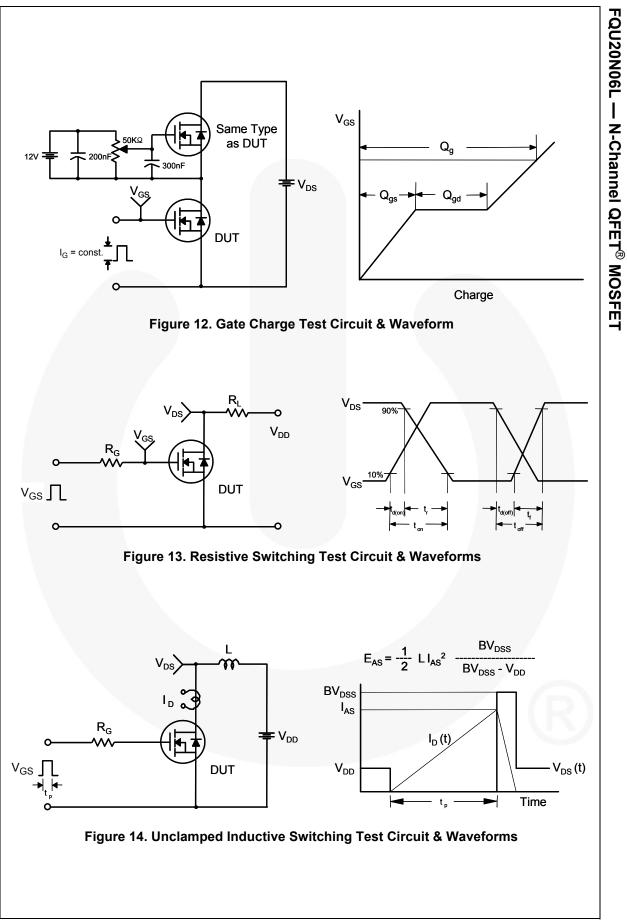
Symbol	Parameter	FQU20N06LTU	Unit
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	3.28	
$R_{\thetaJA}$	Thermal Resistance, Junction to Ambient (Minimum Pad of 2-oz Copper), Max.	110	°C/W
	Thermal Resistance, Junction to Ambient (*1 in <sup>2</sup> Pad of 2-oz Copper), Max.	50	

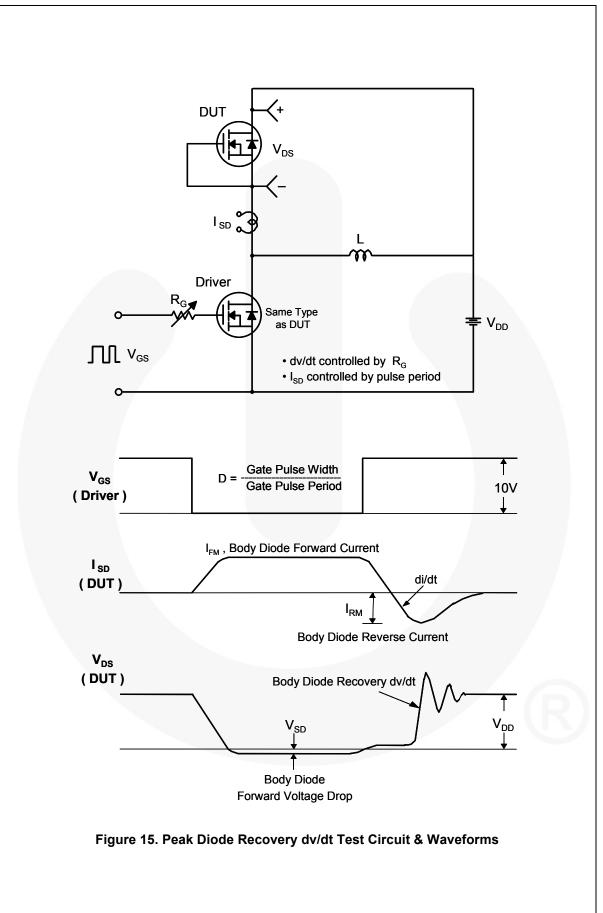
		Package			Size	Tape Width N/A		Quantity	
		IPAK			A			70 units	
lectri	cal Cha	racteristics T <sub>C</sub> :	= 25°C unless of	therwise noted.					
Symbol		Parameter		Test Conditions		Min.	Тур.	Max.	Unit
Off Cha	aracterist	ics							
BV <sub>DSS</sub>	Drain-Sou	rce Breakdown Voltage	V <sub>GS</sub> =	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA		60			V
ΔΒV <sub>DSS</sub> / ΔΤ <sub>J</sub>	C		I <sub>D</sub> = 2	$I_D = 250 \ \mu\text{A}$ , Referenced to 25°C			0.06		V/°C
IDSS			V <sub>DS</sub> =	60 V, V <sub>GS</sub> = 0 V				1	μA
	Zero Gate	Voltage Drain Current	V <sub>DS</sub> =	48 V, T <sub>C</sub> = 125°C				10	μA
I <sub>GSSF</sub>	Gate-Body	y Leakage Current, Forwa	ard V <sub>GS</sub> =	20 V, V <sub>DS</sub> = 0 V				100	nA
I <sub>GSSR</sub>		y Leakage Current, Reve		-20 V, V <sub>DS</sub> = 0 V				-100	nA
On Cha	aracterist	ics							
V <sub>GS(th)</sub>	Gate Thre	shold Voltage	V <sub>DS</sub> =	V <sub>GS</sub> , I <sub>D</sub> = 250 μA		1.0		2.5	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance		00	10 V, I <sub>D</sub> = 8.6 A 5 V, I <sub>D</sub> = 8.6 A			0.046 0.057	0.06 0.075	Ω
9 <sub>FS</sub>	Forward T	ransconductance	V <sub>DS</sub> =	25 V, I <sub>D</sub> = 8.6 A			11		S
								1	
	ic Charac	cteristics					1		
C <sub>iss</sub>	Input Cap	acitance	V <sub>DS</sub> =	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz			480	630	pF
C <sub>oss</sub>	Output Ca	pacitance	f = 1.0				175	230	pF
C <sub>rss</sub>	Reverse T	ransfer Capacitance					35	45	pF
Switch	ing Chara	acteristics							
t <sub>d(on)</sub>	Turn-On D	elay Time	Vpp =	30 V, I <sub>D</sub> = 10.5 A,			10	30	ns
t <sub>r</sub>	Turn-On F	Rise Time	$R_G = 2$	-			165	340	ns
t <sub>d(off)</sub>	Turn-Off D	elay Time					35	80	ns
t <sub>f</sub>	Turn-Off F	all Time			(Note 4)		70	150	ns
-	Total Gate	Charge	V <sub>DS</sub> =	48 V, I <sub>D</sub> = 21 A,			9.5	13	nC
Qg	Gate-Sour	rce Charge	V <sub>GS</sub> =	-			2.5		nC
		n Charge		(Note 4)			5.5		nC
Q <sub>gs</sub>	Gate-Drai	-							
Q <sub>gs</sub> Q <sub>gd</sub>	1								1
Q <sub>gs</sub> Q <sub>gd</sub>	1	ode Characteristic	s and Ma	ximum Ratings					
Q <sub>gs</sub> Q <sub>gd</sub> Drain-S	Source Di	ode Characteristic: Continuous Drain-Source		0				17.2	A
Q <sub>gs</sub> Q <sub>gd</sub> Drain-S	Source Di Maximum		e Diode Forv	vard Current				17.2 68.8	A
Q <sub>gs</sub> Q <sub>gd</sub> Drain-S I <sub>S</sub>	Source Di Maximum Maximum	Continuous Drain-Source	e Diode Forv de Forward	vard Current					
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub> Drain-S I <sub>S</sub> I <sub>SM</sub> V <sub>SD</sub> t <sub>rr</sub>	Source Di Maximum Maximum Drain-Sou	Continuous Drain-Source Pulsed Drain-Source Dio	e Diode Forv de Forward je V <sub>GS</sub> =	vard Current Current				68.8	Α

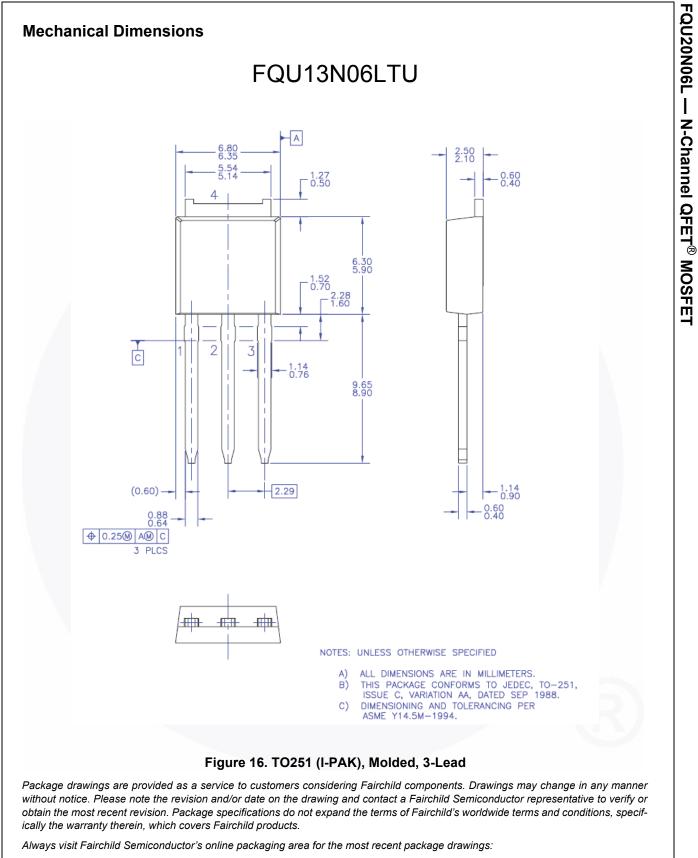
1. Repetitive rating : pulse-width inflied by maximum junction temperatu 2. L = 670  $\mu$ H, I<sub>AS</sub> = 17.2 A, V<sub>DD</sub> = 25 V, R<sub>G</sub> = 25 Ω, starting T<sub>J</sub> = 25°C. 3. I<sub>SD</sub> ≥ 21 A, di/dt ≤ 300 A/ $\mu$ s, V<sub>DD</sub> ≤ BV<sub>PSS</sub>, starting T<sub>J</sub> = 25°C. 4. Essentially independent of operating triperature.











http://www.fairchildsemi.com/package/packageDetails.html?id=PN\_TO251-003



Advance Information	Formative / In Design	may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.
		Rev. 166